

TEST REPORT

Applicant: XPPEN Technology CO.
Address: 15350 FAIRFIELD RANCH RD #G CHINO HILLS,
CA 91709
Equipment Type: Drawing Laptop Magic Stuido 16
Model Name: MS1601 (refer to section 2.3)
Brand Name: XPPEN
FCC ID: 2AKDT-MS1601
Test Standard: 47 CFR Part 15 Subpart B
ANSI C63.4-2014
Sample Arrival Date: Mar 25, 2026
Test Date: Apr. 13, 2026 - May 21, 2026
Date of Issue: Jul. 01, 2026

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

**Tested by:** Gu shuai zhen**Checked by:** Zong Liyao**Approved by:** Liao Jianming
(Technical Director)

Gu shuai zhen.

Zong Liyao

Liao Jianming

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Jul. 01, 2026</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	601, Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☐ Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen, Guangdong
	☒ 1/F., Building B, Ganghongji High-Tech Intelligent Industrial Park, No.1008, Songbai Road, Yangguang Community, Xili Subdistrict, Nanshan District, Shenzhen, Guangdong
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196. The certification body is American Association for Laboratory Accreditation (A2LA).

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	XPPEN Technology CO.
Address	15350 FAIRFIELD RANCH RD #G CHINO HILLS, CA 91709

2.2 Manufacturer Information

Manufacturer	Hanvon Ugee Technology Co., Ltd.
Address	18/F, 19/F, 20/F No.1 Bldg., Longhua Digital Intelligent Manufacturing Center, No. 238 Longsheng Road, Longhua District, Shenzhen

2.3 General Description for Equipment under Test (EUT)

EUT Name	Drawing Laptop Magic Stuido 16
Model Name Under Test	MS1601
Series Model Name	MS1601, MS1602, MS1603, MS1604
Description of Model name differentiation	All models are same with electrical parameters and internal circuit structure, but only differ in model name. (this information provided by the applicant)
Hardware Version	N/A
Software Version	N/A
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Ancillary Equipment 1	Li-Polymer Battery	
	Brand Name	N/A
	Model No.	AEC359294B-3S1P
	Serial No.	N/A
	Capacitance	5050mAh, 58.33Wh
	Rated Voltage	11.55 V
	Limited Voltage	13.2 V
	Manufacturer	Apower Electronics Co., Ltd.
Ancillary Equipment 2	Power Supply Unit	
	Brand Name	N/A
	Model No.	PD0657C-0653
	Serial No.	N/A
	Rated Input	100-240V~, 50-60Hz, 1.5A Max.
	Rated Output	5VDC 3A, 9VDC 3A, 12VDC 3A, 15VDC 3.0A, 20VDC 3.25A 65W Max.
	Manufacturer	Shenzhen ABP Technology Co., Ltd.
Ancillary Equipment 3	USB Cable	

	Model No.	N/A
	Length (Approx.)	1.5 m

2.5 Technical Information

Network and Wireless connectivity	Bluetooth (BR+EDR+BLE) WIFI 802.11a, 802.11b, 802.11g, 802.11n(HT20/40), 802.11ac(VHT20/40/80/160), 802.11ax(HE20/40/80/160)
Classification of equipment	Class B
The highest internal frequency of EUT	5850 MHz

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	--
2	Conducted Emission, AC Ports	15.107	Pass	--

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.

Measurement	Value
Conducted emissions (9 kHz-150 KHz)	3.36 dB
Conducted emissions (150 kHz-30 MHz)	2.92 dB
Radiated emissions (30 MHz-1 GHz)	4.24 dB
Radiated emissions (1 GHz-6 GHz)	5.10 dB
Radiated emissions (6 GHz-18 GHz)	5.30 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
3.5mm Earphone	VIVO	N/A	N/A	N/A	N/A	☒
Data connector	HBR	type-c to USB 3.0	N/A	N/A	N/A	☒
USB disk	Sandisk	CZ73-32G	N/A	N/A	N/A	☒
Laptop	HONOR	N/A	N/A	N/A	N/A	☒
Phone	HONOR	V20	N/A	N/A	N/A	☒

4.2 Test Configurations

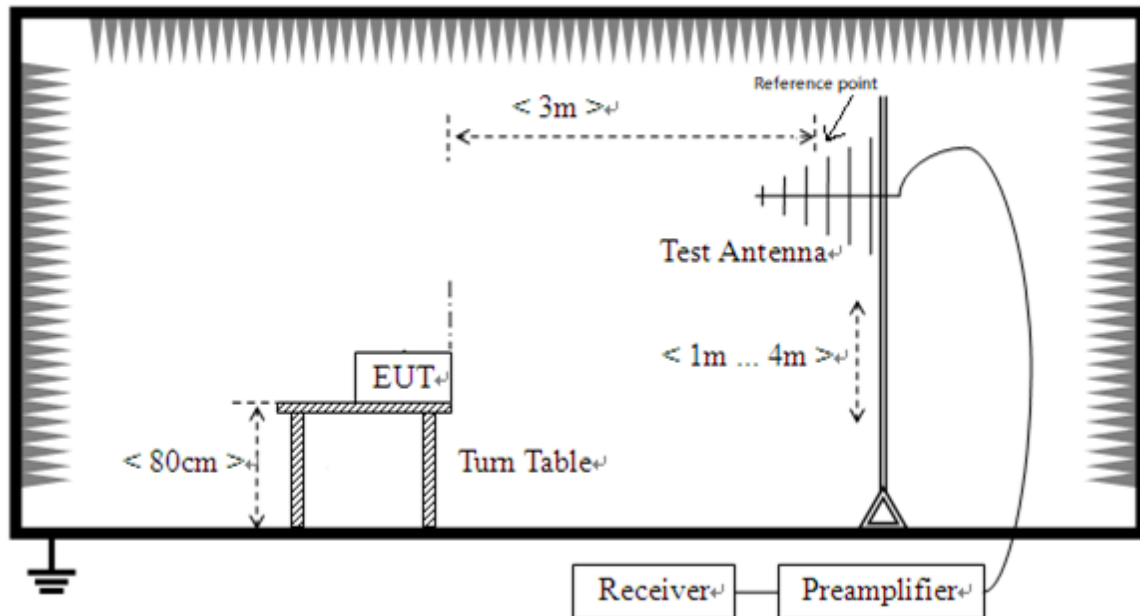
All test modes of EUT are listed in the table below.

Test Mode Configuration	Description
Mode 1	<u>The Front Camera Test Mode</u> EUT + Adapter + USB Cable + Battery
Mode 2	<u>The H-pattern Test Mode</u> EUT + Adapter + USB Cable + Battery
Mode 3	<u>The Charging Test Mode</u> EUT + Adapter + USB Cable + Battery
Mode 4	<u>The 3.5mm Earphone Test Mode</u> EUT + 3.5mm Earphone
Mode 5	<u>The OTG Test Mode</u> EUT + Battery + Data connector + USB Disk
Mode 6	<u>The Drawing tablet Test Mode</u> EUT + USB Cable+Battery +Laptop
Mode 7	<u>The Reverse wireless charging Test Mode</u> EUT+USB Cable+Phone
Mode 8	<u>The Only Test Mode</u> EUT

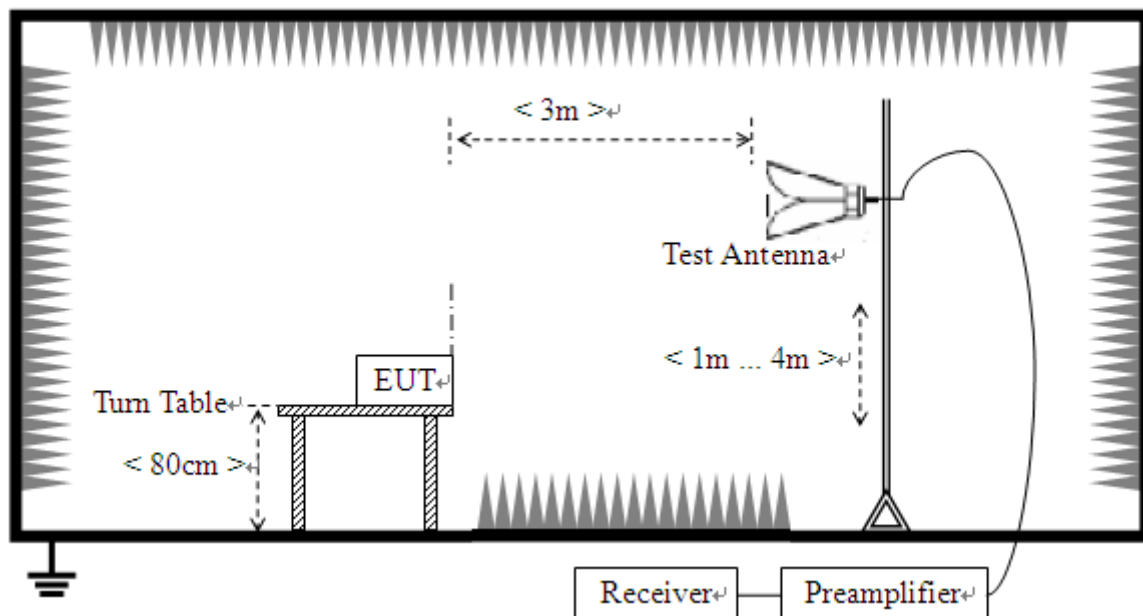
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 8	2
Conducted Emission, AC Ports	Mode 1~Mode 8	2
Note: All operation modes were tested, but only test data of the worst mode was presented in this report.		

4.3 Test Setups

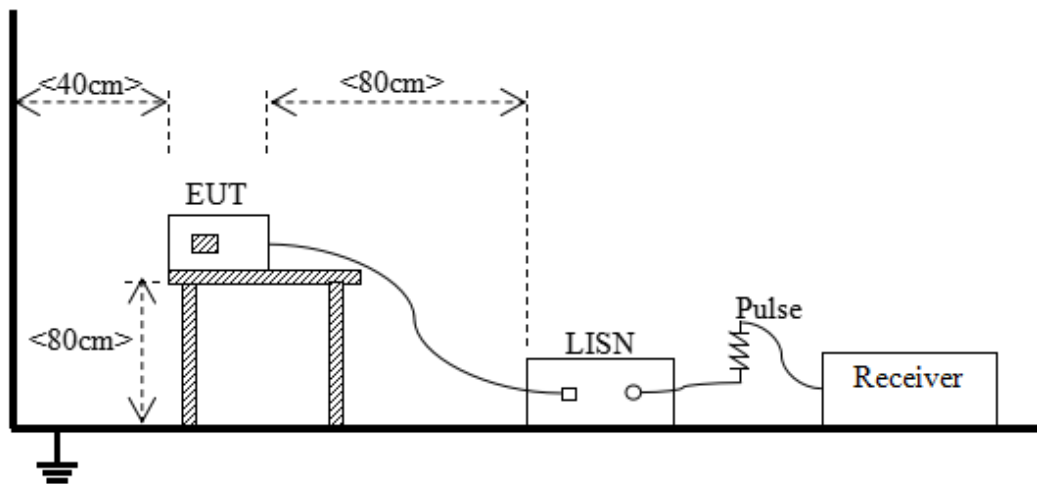
Test Setup 1



Radiated Emission (30 MHz-1 GHz)



Radiated Emission (above 1 GHz)

Test Setup 2

Conducted Emissions, AC Ports

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class A (at 3 m)
	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log [\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)	Class B (at 3 m)			Class A (at 3 m)	
	Field Strength ($\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)
1 - F_M	500	54	74	60	80

Note 1: The highest measurement frequency, F_M , in GHz, shall be determined as next Table.

Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula:
 $L_{3m} = L_{10m} + 20 \cdot \log(d_{10m}/d_{3m})$
 Where:
 L_{3m} is Average Class A limit at 3m;
 L_{10m} is Average Class A limit at 10m;
 d_{10m} is Measurement distance in 10m;
 d_{3m} is Measurement distance in 3m.
 For this case: $L_{3m} = 49.5 + 20 \cdot \log(10/3) = 60$ (dB $\mu\text{V/m}$).

Highest internal frequency (F_X)	Highest measurement frequency (F_M)
$F_X \leq 108 \text{ MHz}$	1 GHz
$108 \text{ MHz} \leq F_X \leq 500 \text{ MHz}$	2 GHz
$500 \text{ MHz} \leq F_X \leq 1 \text{ GHz}$	5 GHz
$F_X \geq 1 \text{ GHz}$	$5 * F_X$ or 40 GHz, whichever is lower.
Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.	

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360° , and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for $f \geq 1 \text{ GHz}$, 100 kHz for $f < 1 \text{ GHz}$

VBW $\geq$ RBW

Sweep = auto

Detector function = peak for $f < 1 \text{ GHz}$, peak & RMS Average for $f \geq 1 \text{ GHz}$

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.

NOTE:

1. Results (dB μ V/m) = Reading (dB μ V) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Margin = Limit - Results

5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW $\geq$ RBW

Sweep = 10ms

Detector function = peak & Average

Trace = max hold

5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results (dBμV) = Reading (dBμV) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Margin = Limit - Results

ANNEX A TEST RESULTS

A.1 Radiated Emission

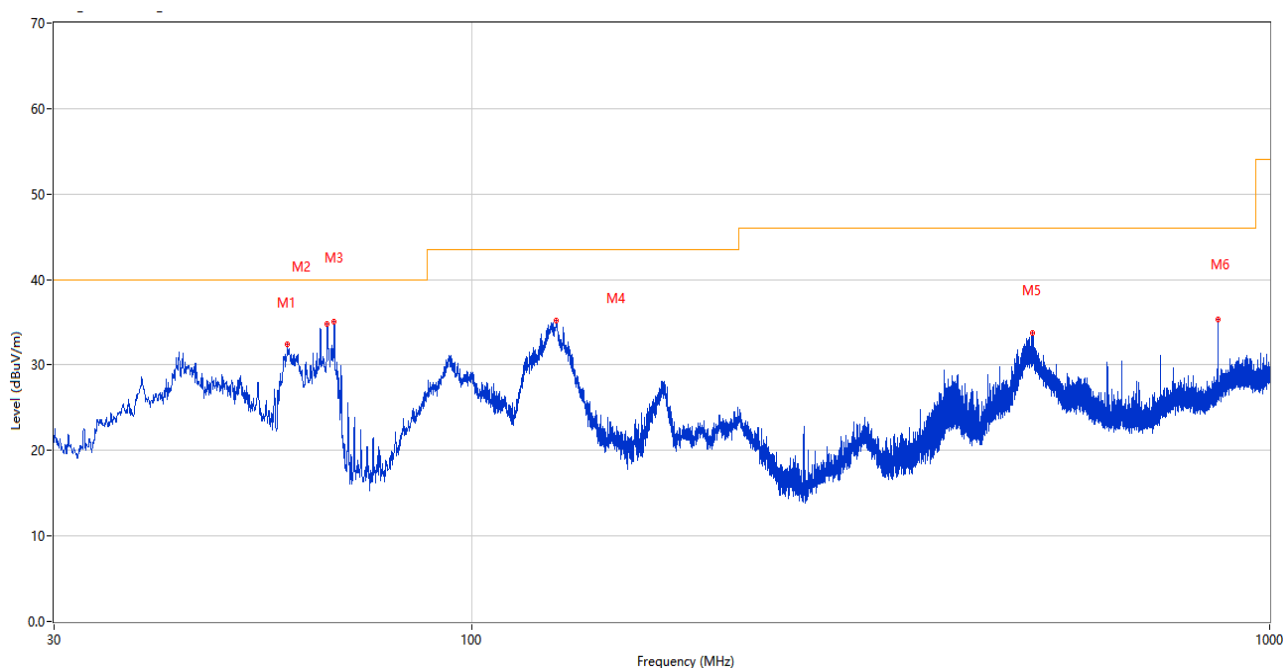
Note 1: The symbol of "--" in the table which means not application.

Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Sample No.	S01	Temperature	22.6℃
Humidity	53%RH	Pressure	101kPa
Test Engineer	Zhong Pingqi	Test Date	2026.04.02

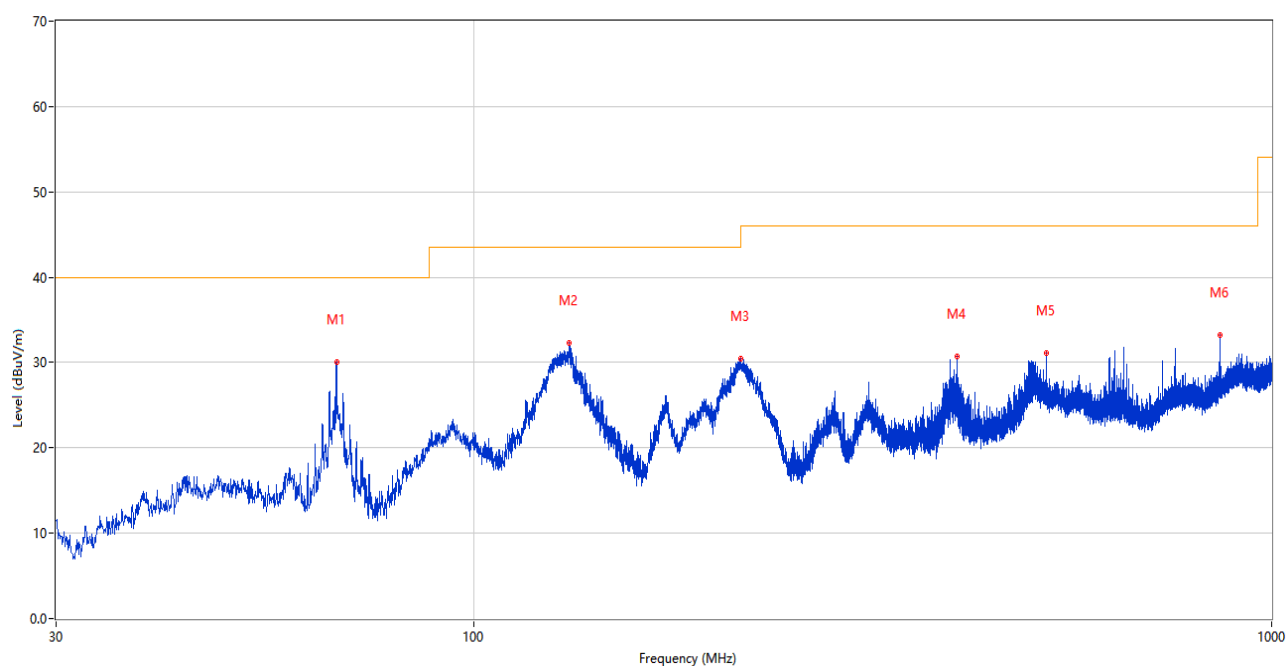
Test Mode 2

1) Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	58.809	32.37	-25.67	40.0	7.63	Peak	17.00	100	Vertical	Pass
2	65.987	34.85	-28.08	40.0	5.15	Peak	222.00	100	Vertical	Pass
3	67.345	35.03	-28.07	40.0	4.97	Peak	150.00	200	Vertical	Pass
4	127.728	35.22	-29.44	43.5	8.28	Peak	186.00	100	Vertical	Pass
5	504.233	33.80	-17.86	46.0	12.20	Peak	286.00	100	Vertical	Pass
6	861.047	35.27	-10.38	46.0	10.73	Peak	64.00	200	Vertical	Pass

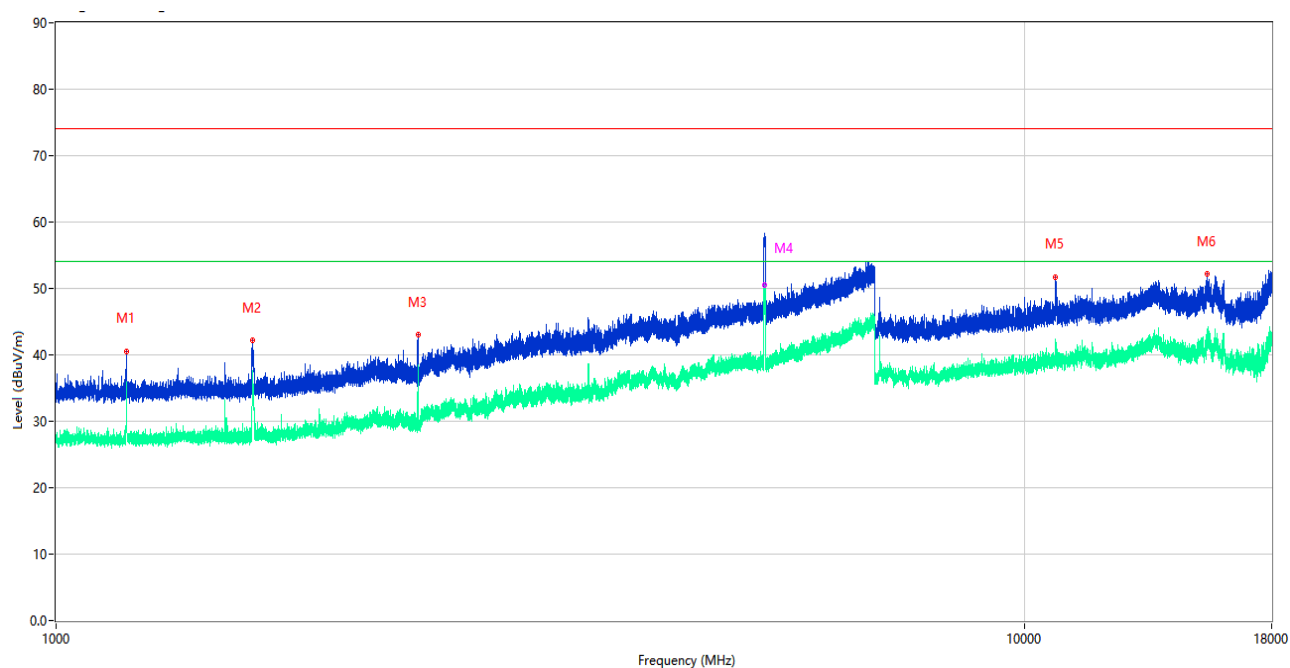
2) Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	67.394	30.06	-28.06	40.0	9.94	Peak	209.00	200	Horizontal	Pass
2	131.898	32.34	-29.77	43.5	11.16	Peak	78.00	200	Horizontal	Pass
3	216.240	30.51	-26.22	46.0	15.49	Peak	257.00	100	Horizontal	Pass
4	403.402	30.72	-20.44	46.0	15.28	Peak	294.00	100	Horizontal	Pass
5	521.790	31.09	-17.89	46.0	14.91	Peak	293.00	200	Horizontal	Pass
6	861.047	33.23	-10.38	46.0	12.77	Peak	337.00	100	Horizontal	Pass

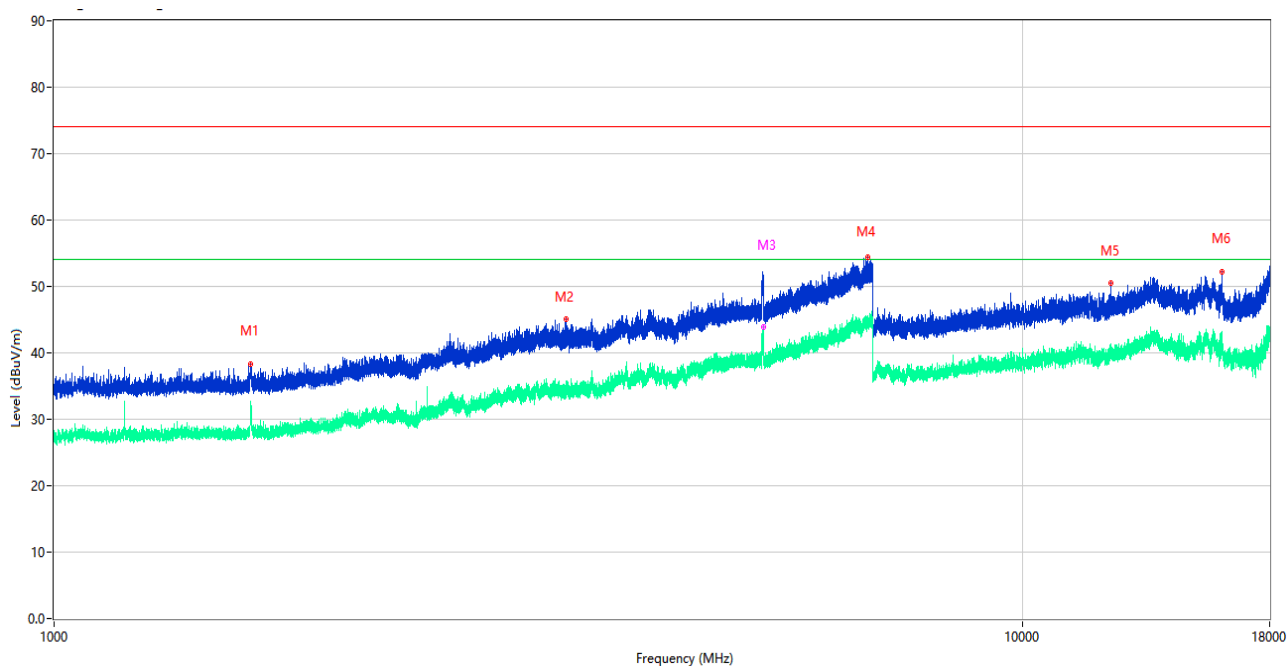
Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Below 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330121	2025.12.26	2026.12.25	☒
Test Antenna-Bi-Log	SCHWARZB ECK	VULB 9163	01414	2023.11.03	2026.11.02	☒
Anechoic Chamber	EMC Electronic Co., Ltd	C8-966	107	2024.05.12	2027.05.11	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

3) Test Antenna Vertical, 1 GHz – 18GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1182.130	40.53	-17.88	74.0	33.47	Peak	256.00	100	Vertical	Pass
1**	1182.130	35.32	-17.88	54.0	18.68	AV	256.00	100	Vertical	Pass
2	1594.100	42.20	-17.94	74.0	31.80	Peak	278.00	100	Vertical	Pass
2**	1594.100	34.30	-17.94	54.0	19.70	AV	278.00	100	Vertical	Pass
3	2364.610	43.04	-13.99	74.0	30.96	Peak	124.00	100	Vertical	Pass
3**	2364.610	38.44	-13.99	54.0	15.56	AV	124.00	100	Vertical	Pass
4	5396.730	57.67	-3.46	74.0	16.33	Peak	266.00	100	Vertical	Pass
4**	5396.730	50.54	-3.46	54.0	3.46	AV	266.00	100	Vertical	Pass
5	10769.700	51.72	2.62	74.0	22.28	Peak	263.00	100	Vertical	Pass
5**	10769.700	41.17	2.62	54.0	12.83	AV	263.00	100	Vertical	Pass
6	15443.599	52.14	6.75	74.0	21.86	Peak	189.00	100	Vertical	Pass
6**	15443.599	43.84	6.75	54.0	10.16	AV	189.00	100	Vertical	Pass

4) Test Antenna Horizontal, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1594.750	38.36	-17.95	74.0	35.64	Peak	192.00	100	Horizontal	Pass
1**	1594.750	32.12	-17.95	54.0	21.88	AV	192.00	100	Horizontal	Pass
2	3381.080	45.08	-8.79	74.0	28.92	Peak	200.00	100	Horizontal	Pass
2**	3381.080	35.52	-8.79	54.0	18.48	AV	200.00	100	Horizontal	Pass
3	5397.750	49.18	-3.46	74.0	24.82	Peak	349.00	100	Horizontal	Pass
3**	5397.750	43.87	-3.46	54.0	10.13	AV	349.00	100	Horizontal	Pass
4	6917.380	54.48	0.65	74.0	19.52	Peak	241.00	100	Horizontal	Pass
4**	6917.380	43.83	0.65	54.0	10.17	AV	241.00	100	Horizontal	Pass
5	12331.700	50.45	4.07	74.0	23.55	Peak	113.00	100	Horizontal	Pass
5**	12331.700	39.88	4.07	54.0	14.12	AV	113.00	100	Horizontal	Pass
6	16061.250	52.24	8.44	74.0	21.76	Peak	0.00	100	Horizontal	Pass
6**	16061.250	41.41	8.44	54.0	12.59	AV	0.00	100	Horizontal	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Above 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330121	2025.12.26	2026.12.25	☒
Test Antenna-Horn	SCHWARZB ECK	BBHA 9120D	02459	2023.10.26	2026.10.25	☒
Anechoic Chamber	EMC Electronic Co., Ltd	C8-966	107	2024.05.12	2027.05.11	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

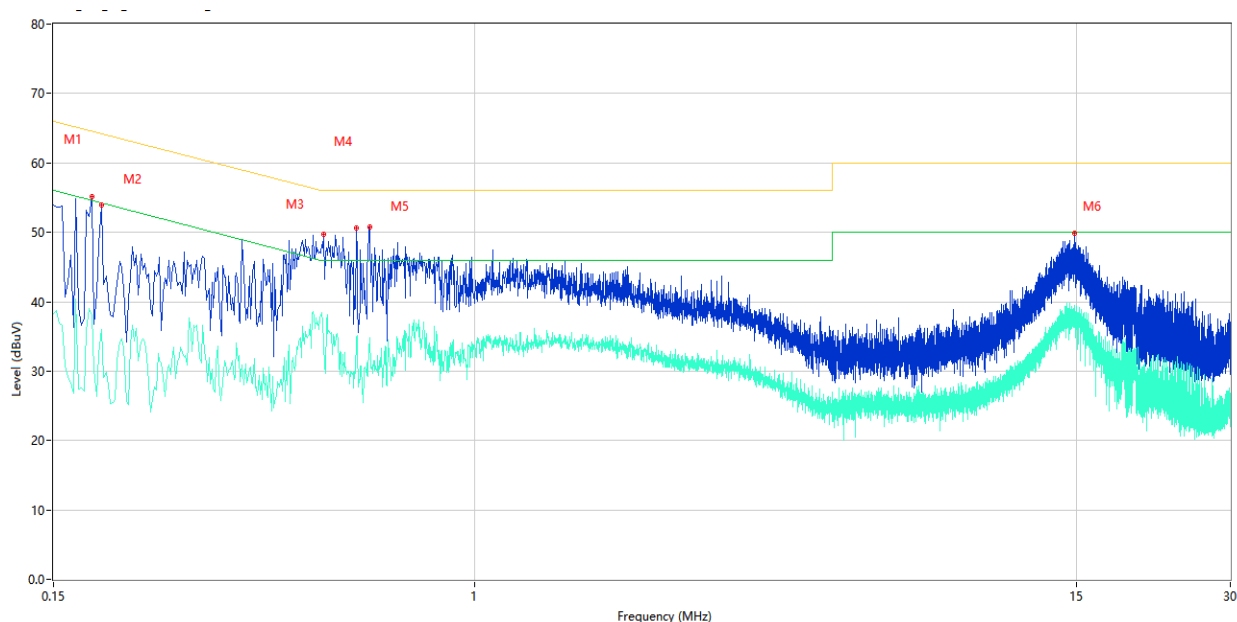
A.2 Conducted Emission, AC Ports

Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.

Sample No.	S01	Temperature	22.6℃
Humidity	53%RH	Pressure	100.6kPa
Test Engineer	Zhong Pingqi	Test Date	2026.04.02

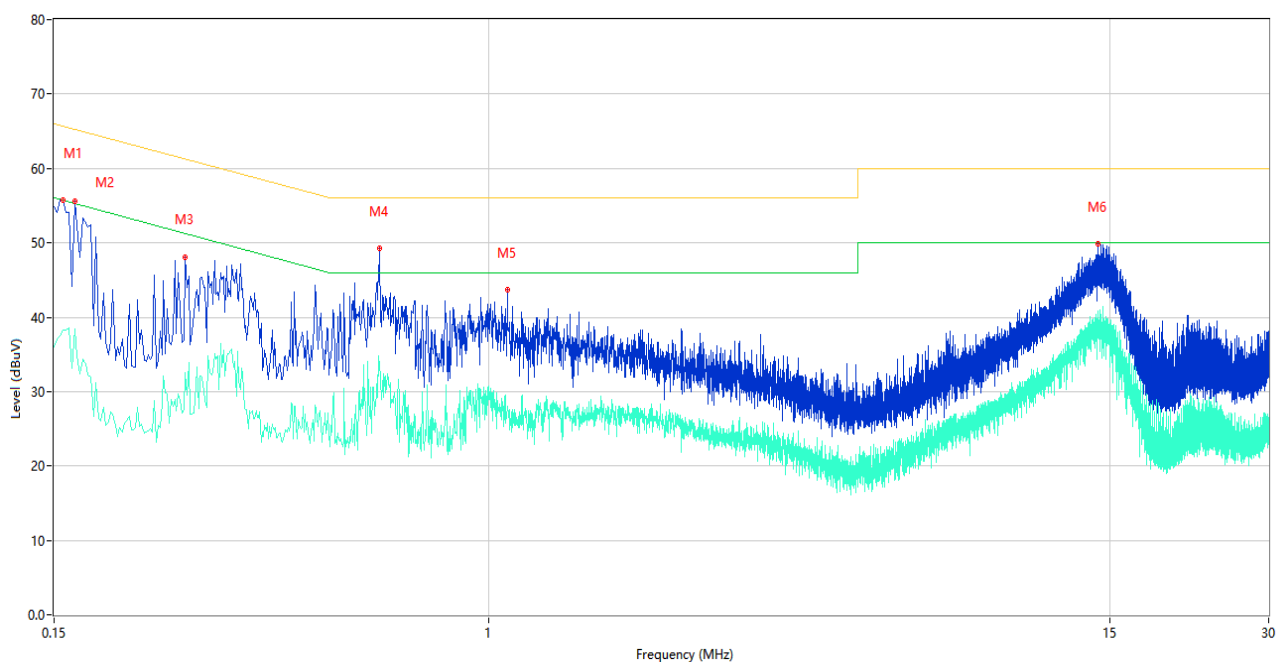
Test Mode 2

1) AC Ports - L Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.178	55.11	10.26	64.58	9.47	Peak	L	Pass
1**	0.178	38.06	10.26	54.58	16.52	AV	L	Pass
2	0.186	53.87	10.25	64.21	10.34	Peak	L	Pass
2**	0.186	35.97	10.25	54.21	18.24	AV	L	Pass
3	0.506	49.74	10.25	56.00	6.26	Peak	L	Pass
3**	0.506	33.88	10.25	46.00	12.12	AV	L	Pass
4	0.586	50.58	10.26	56.00	5.42	Peak	L	Pass
4**	0.586	34.80	10.26	46.00	11.20	AV	L	Pass
5	0.622	50.75	10.26	56.00	5.25	Peak	L	Pass
5**	0.622	33.89	10.26	46.00	12.11	AV	L	Pass
6	14.870	49.88	12.95	60.00	10.12	Peak	L	Pass
6**	14.870	38.71	12.95	50.00	11.29	AV	L	Pass

2) AC Ports - N Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.156	55.79	10.18	65.67	9.88	Peak	N	Pass
1**	0.156	38.22	10.18	55.67	17.45	AV	N	Pass
2	0.164	55.56	10.17	65.26	9.70	Peak	N	Pass
2**	0.164	38.37	10.17	55.26	16.89	AV	N	Pass
3	0.266	48.12	10.16	61.24	13.12	Peak	N	Pass
3**	0.266	32.54	10.16	51.24	18.70	AV	N	Pass
4	0.620	49.25	10.17	56.00	6.75	Peak	N	Pass
4**	0.620	33.59	10.17	46.00	12.41	AV	N	Pass
5	1.084	43.69	10.21	56.00	12.31	Peak	N	Pass
5**	1.084	27.59	10.21	46.00	18.41	AV	N	Pass
6	14.262	49.94	12.75	60.00	10.06	Peak	N	Pass
6**	14.262	37.16	12.75	50.00	12.84	AV	N	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9038B	MY61380132	2025.12.26	2026.12.25	☒
LISN	SCHWARZBECK	NSLK 8127	01009	2025.07.15	2026.07.14	☒
Shielded Room	YiHeng Electronic Co., Ltd	/	235	2024.11.05	2027.11.04	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

ANNEX B TEST SETUP PHOTOS

Please refer the document “Ti-CC26030305-AE.PDF”.

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document “Ti-CC26030305-AW.PDF”.

ANNEX D EUT INTERNAL PHOTOS

Please refer the document “Ti-CC26030305-AI.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
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--END OF REPORT--